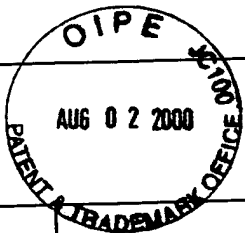



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|--|----|--------------|---|---|---|---|---|------|---------|--|-------------|---------------------------|-------------------------|--|
| Sheet <u>1</u> of <u>1</u> SECOND LIST OF REFERENCES CITED BY APPLICANT (REVISED FORM PTO-1449) DATED: July 31, 2000 | | | | | | | | | | Atty. Docket No. 3905 | | Serial No.: 09/519,408 | | |
| | | | | | | | | | | Applicant: Takao NAKAMURA et al. | | | | |
| | | | | | | | | | | U.S. Filing Date: March 3, 2000 | | Art Unit: 2811 | | |
| <div style="display: flex; justify-content: space-around; align-items: center;"> <div style="text-align: center;">  </div> <div>U. S. PATENT DOCUMENTS</div> </div> | | | | | | | | | | | | | | |
| *EXAMINER INITIAL | | DOCUMENT NO. | | | | | | DATE | NAME | Cl. | Sub- Cl. | Fil. Date | | |
| | | | | | | | | | | - | - | - | | |
| FOREIGN PATENT DOCUMENTS | | | | | | | | | | | | | | |
| | | DOCUMENT NO. | | | | | | DATE | COUNTRY | Cl. | Sub- Cl. | Trans. | | |
| | | | | | | | | | | | | Yes | No | |
| WSL | AB | 09 | 0 | 5 | 9 | 7 | 6 | 2 | 03/1997 | Japan | - | - | x (Abstract) | |
| WSL | AC | 2000 | - | 4 | 4 | 2 | 3 | 6 | 02/2000 | Japan | - | - | x (Partial Translation) | |
| OTHER DOCUMENTS | | | | | | | | | | | | | | |
| | | | | | | | | | | | | | | |
| EXAMINER  | | | | | | | | | | DATE CONSIDERED 5/21/01 | | | | |
| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | | | | | | | | | |

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Applicant: Takao NAKAMURA et al.

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March 3, 2000

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| | | DOCUMENT NO. | DATE | COUNTRY | Cl. | Sub- Cl. | Trans. | |
|-----|----|----------------|---------|---------|-----|-------------|-------------|----|
| | | | | | | | Yes | No |
| WSE | AA | 6- 3 1 8 4 0 6 | 11/1994 | Japan | - | - | X (abst) | |
| | | | | | | | | |

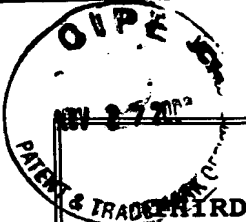
OTHER DOCUMENTS

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No. 3905

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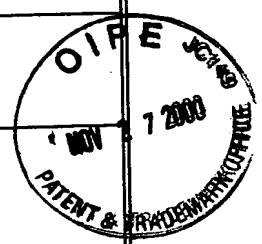
(REVISED FORM PTO-1449)

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2811



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| | | | | | | | Yes | No |
| USL | AD | 05 1 3 9 7 3 5 | 06/1993 | Japan | - | - | X (Abstract) | X |

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